PATENT

Our Docket: M-CI 4561

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Ger van den Engh

Serial No: 09/847,466

Filed: May 1, 2001

For: APPARATUS FOR DETERMINING)

RADIATION BEAM ALIGNMENT

Commissioner for Patents Washington, D.C.

Group Art Unit: 287

Examiner: S. Lee

I hereby certify that this correspondence is being deposited with the United States-Postal Service as first class mail, in an envelope addressed to: The Commissioner for Patents, Washington, D.C. 20231:

Oct. 22, 2002 (date of deposit)

Dellies

RESPONSE TO OFFICE ACTION

Responsive to the Office Action mailed July 22, 2002, entry of the following Amendments and Remarks is respectfully requested.

## AMENDMENTS

In the specification

Please replace the paragraph starting on page 20, line 28 and ending on page 21, line 21, with the following paragraph:

An apparatus of the invention can be used to determine alignment of a radiation beam emitted from a flow chamber. flow chamber can contain a sample stream in which emission from molecules or particles is observed when they pass a point of observation. The point of observation can be placed, for example, as shown in Figures 2 and 4 as location 4. As shown in the Figures, radiation emitted at the point of observation, for example, from fluorescent particles that have been contacted with radiation of an excitatory wavelength, can be collimated into a beam. The beam can be directed toward a screen having a mirrored surface interrupted by one or more pin holes such that alignment

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